## \* PATENT APPLICATION

FORM PTO-1449	ATTY. DKT NO.	01-537	SER. NO.
	APPLICANT	TAGUCHI et al.	
	FILING DATE	January 6, 2004	GROUP

#### REFERENCE DESIGNATION

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• Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX.

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FORM PTO-1449	ATTY. DKT	01-537	SER. NO.	10/751,499
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	FILING DATE	January 6, 2004	GROUP	3661

#### REFERENCE DESIGNATION

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<sup>\*</sup> Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX.

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DT		Notification of Reason(s) for Refusal from Japanese Patent Office issued on October 3, 2006 for the corresponding Japanese patent application No. 2003-003240 (a copy and English translation thereof)					
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